AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions and listings of claims in the application:

LISTING OF CLAIMS:

1. (currently amended): A phase shifting wavefront superimposition method, in particular a phase shifting interferometry method, for wavefront measurement of optical imaging systems, whereincomprising:

registering intensities (I_n) of superimposition patterns of object wavefronts and reference wavefronts for a predefined location, wherein the superimposition patterns are produced successively inover time with respective phase shifting by shifts having predefined phase steps (φ_n) for a respectively predefined location;

from the registered intensities, determining an object-induced phase difference (ϕ) between the object wavefronts and the reference wavefronts for the respective location;

determining phase shift errors $(\delta \phi_n)$ in the superimposition patterns produced successively by means of a spatial superimposition pattern evaluation; and

correctively utilizing the determined phase shift errors in determining the objectinduced phase difference (φ) by correctively utilizing the determined phase shift errors.

2. (currently amended): The phase shifting wavefront superimposition method according to claim 1, wherein predefined phase jumps in an at least one-dimensionally periodic

structure are used to provide at least one of the object wavefronts or and the reference wavefronts in the determination of the phase shift errors.

- 3. (currently amended): The phase shifting wavefront superimposition method according to claim 1 or 2, wherein, in order to said correctively utilize utilizing the phase shift errors in the determination of determining the object-induced phase difference, comprises determining compensating correction contributions $(\delta \phi_n)(\delta \omega_n)$ to apodisation weights $(\phi_n)(\omega_n)$ are determined and used using the apodisation weights in a relationship equation of the object-induced phase difference as a function of the superimposition pattern intensity.
- 4. (previously presented): The phase shifting wavefront superimposition method according to claim 1 or 2, wherein the method is configured as a phase shifting interferometry method for wavefront measurement of an optical imaging system.
- 5. (new): A phase shifting wavefront superimposition method, comprising:

 determining pattern intensities of temporally successive superimposition patterns of
 reference and object wavefronts for a predetermined location, where each successive pattern is
 obtained by phase shifting the object and reference wavefronts relative to one another;

determining phase shift errors in the temporally successive superimposition patterns using spatial superimposition pattern evaluation; and

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determining an object-induced phase difference between the object wavefronts and the reference wavefronts for the predetermined location from the pattern intensities and utilizing the determined phase shift errors for correction.